

Notic of References Cit d	Application/Control No. 10/040,797	Applicant(s)/Patent Under Reexamination GOLDFINE ET AL.	
	Examiner Jeffrey R. West	Art Unit 2857	Page 1 of 1

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	C	US-5,223,796	06-1993	Waldman et al.	324/687
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.